

Fabrication of oxide nanoparticles using oxidation of magnetic alloys in polyimide

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Oxide nanoparticles embedded in a polyimide (PI) matrix was fabricated by oxidizing a layer of $\text{Ni}_{80}\text{Fe}_{20}$ ($\text{Co}_{80}\text{Fe}_{20}$) metal film sandwiched between two PI precursor layers. Oxide nanoparticles nucleated in the PI matrix as a by-product of the imidization process. The 3.5 nm-thick $\text{Ni}_{80}\text{Fe}_{20}$ film was converted into a mono-layer of NiO oxide particles whose average size was 4.5 nm in diameter. When the metal film thickness was above 3.5 nm, a continuous layer of the metal film was found with selectively oxidized regions along the grain boundary. Similar observation was previously made when the $\gamma\text{-Fe}_2\text{O}_3$ particles were produced using the same reaction [1,2]. In case of the $\text{Co}_{80}\text{Fe}_{20}$ thin film, the oxide particles were composed of Co_3O_4 with spinel structure. These Co_3O_4 particles were, however, rather irregularly shaped with a wide size distribution whereas the NiO nanoparticles had spherical shapes with much narrower size distribution. X-ray photoelectron spectroscopy of oxide nanoparticles showed that the particles had a varying degree of metallic residue, suggesting that these nanoparticles could have metallic cores, surrounded by an oxide layer. Comparing with the $\gamma\text{-Fe}_2\text{O}_3$ particles produced using the same procedure, relatively larger amount of metallic residue was detected from the NiO and Co_3O_4 particles, which explains the higher magnetic moment measured from the NiO and Co_3O_4 particles.

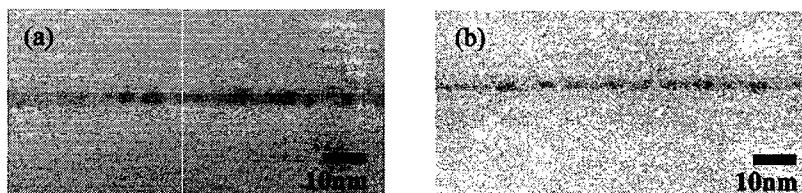


Fig 1. Cross-sectional TEM images of the nanoparticles: (a) NiO, (b) Co_3O_4

References

- [1] Sung K. Lim et al., *J. Colloid Interface Sci.* (in press)
- [2] Y. M. Chiang et al., *Physical Ceramics* (John Wiley & Sons, Inc., New York, 1997), p. 368.